

December 2011

FDMQ8203

GreenBridgeTM Series of High-Efficiency Bridge Rectifiers Dual N-Channel and Dual P-Channel PowerTrench[®] MOSFET N-Channel: 100 V, 6 A, 110 m Ω P-Channel: -80 V, -6 A, 190 m Ω

Features

Q1/Q4: N-Channel

■ Max $r_{DS(on)}$ = 110 m Ω at V_{GS} = 10 V, I_D = 3 A

■ Max $r_{DS(on)}$ = 175 m Ω at V_{GS} = 6 V, I_D = 2.4 A

Q2/Q3: P-Channel

■ Max $r_{DS(on)}$ = 190 m Ω at V_{GS} = -10 V, I_D = -2.3 A

■ Max $r_{DS(on)} = 235 \text{ m}\Omega$ at $V_{GS} = -4.5 \text{ V}$, $I_D = -2.1 \text{ A}$

■ Substantial efficiency benefit in PD solutions

■ RoHS Compliant

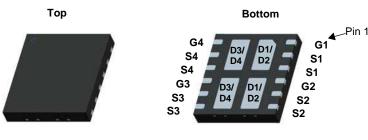


General Description

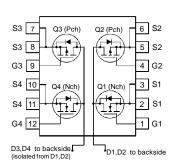
This quad mosfet solution provides ten-fold improvement in power dissipation over diode bridge.

Application

■ High-Efficiency Bridge Rectifiers







MOSFET Maximum Ratings T_A = 25 ℃ unless otherwise noted

Symbol	Parameter	Parameter		Q1/Q4	Q2/Q3	Units
V _{DS}	Drain to Source Voltage			100	-80	V
V_{GS}	Gate to Source Voltage			±20	±20	V
	Drain Current -Continuous (Package limited)	T _C = 25 ℃		6	-6	
	-Continuous (Silicon limited)	T _C = 25 ℃		10	-10	A
ID	-Continuous	T _A = 25 ℃	(Note 1a)	3.4	-2.6	
	-Pulsed			12	-10	
Б	Power Dissipation for Single Operation	T _C = 25 ℃		22	37	W
P_{D}	Power Dissipation for Dual Operation $T_A = 25 ^{\circ}\text{C}$ (Note 1a)		2.	5	VV	
T _J , T _{STG}	Operating and Storage Junction Temperature Range	ge		-55 to +150		C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	€/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	160	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMQ8203	FDMQ8203	MLP4.5x5	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25 \text{ } \text{C}$ unless otherwise noted

Parameter	Test Conditions	Туре	Min	Тур	Max	Units
octeristics						
Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = -250 \mu A, V_{GS} = 0 V$	Q1/Q4 Q2/Q3	100 -80			V
Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C I_D = -250 μA, referenced to 25 °C	Q1/Q4 Q2/Q3		72 -79		mV/℃
Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V V _{DS} = -64 V, V _{GS} = 0 V	Q1/Q4 Q2/Q3			1 -1	μ Α μ Α
Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V	Q1/Q4 Q2/Q3			±100 ±100	nA nA
	Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Total cases Incteristics Drain to Source Breakdown Voltage	Drain to Source Breakdown Voltage $I_D = 250 \mu A, V_{GS} = 0 \text{ V}$ $Q1/Q4 100 \text{ P}$ $Q2/Q3 -80 $	Drain to Source Breakdown Voltage $I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}$ $Q1/Q4 = 100 \text{Q2}/Q3 = -80$ Breakdown Voltage Temperature $I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}$ $Q1/Q4 = -70 \text{Q2}/Q3 = -80$ Breakdown Voltage Temperature $I_D = 250 \mu\text{A}, \text{referenced to } 25 \text{C}$ $Q1/Q4 = -70 \text{Coefficient}$ $V_{DS} = 80 \text{V}, V_{GS} = 0 \text{V}$ $V_{DS} = -64 \text{V}, V_{GS} = 0 \text{V}$ $V_{DS} = -64 \text{V}, V_{GS} = 0 \text{V}$ $V_{DS} = -64 \text{V}, V_{DS} = -64 \text{V}$ $V_{DS} $	The proof of th

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, \ I_D = 250 \ \mu A$ $V_{GS} = V_{DS}, \ I_D = -250 \ \mu A$	Q1/Q4 Q2/Q3	2 -1	3 -1.6	4 -3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C I_D = -250 μA, referenced to 25 °C	Q1/Q4 Q2/Q3		-8 5		mV/℃
_	Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, \ I_D = 3 \text{ A}$ $V_{GS} = 6 \text{ V}, \ I_D = 2.4 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 3 \text{ A}, \ T_J = 125 \text{ C}$	Q1/Q4		85 118 147	110 175 191	mO.
r _{DS(on)}	Diam to Source On Resistance	V_{GS} = -10 V, I_{D} = -2.3 A V_{GS} = -4.5 V, I_{D} = -2.1 A V_{GS} = -10 V, I_{D} = -2.3 A, T_{J} = 125 °C	Q2/Q3		161 188 273	190 235 323	mΩ
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_D = 3 \text{ A}$ $V_{DS} = -10 \text{ V}, I_D = -2.3 \text{ A}$	Q1/Q4 Q2/Q3		6 6		S

Dynamic Characteristics

-						
C _{iss}	Input Capacitance	Q1/Q4:	Q1/Q4	158	210	PΓ
O _{ISS}	input dapacitance	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q2/Q3	639	850	Pi
0	Output Canaditanes		Q1/Q4	41	55	~F
Coss	Output Capacitance	Q2/Q3:	Q2/Q3	46	65	pF
C	Dougras Transfer Conscitones	$V_{DS} = -40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1/Q4	2.6	5	~F
C _{rss}	Reverse Transfer Capacitance		Q2/Q3	24	40	pF

Switching Characteristics

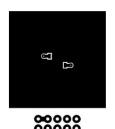
t _{d(on)}	Turn-On Delay Time	Q1/Q4:	Q1/Q4 Q2/Q3	3.8 4.7	10 10	ns
t _r	Rise Time	$V_{DD} = 50 \text{ V}, I_{D} = 3 \text{ A}, V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	Q1/Q4 Q2/Q3	1.3 2.8	10 10	ns
t _{d(off)}	Turn-Off Delay Time	Q2/Q3: V _{DD} = -40 V, I _D = -2.3 A,	Q1/Q4 Q2/Q3	7.5 22	15 35	ns
t _f	Fall Time	$V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$	Q1/Q4 Q2/Q3	1.9 2.7	10 10	ns
Qg	Total Gate Charge	VGS = 0 V to 10 V VGS = 0 V to -10 V Q1/Q4:	Q1/Q4 Q2/Q3	2.9 13	5 19	nC
Q _g	Total Gate Charge	VGS = 0 V to 5 V VGS = 0 V to -4.5 V $V_{DD} = 50 V,$ $V_{DD} = 3 A$	Q1/Q4 Q2/Q3	1.6 6.4	3 10	nC
Q _{gs}	Gate to Source Gate Charge	Q2/Q3: V _{DD} = -40 V	Q1/Q4 Q2/Q3	0.8 1.6		nC
Q_{gd}	Gate to Drain "Miller" Charge	$I_{D} = -2.3A$	Q1/Q4 Q2/Q3	0.8 2.6		nC

Electrical Characteristics $T_J = 25 \text{ } \text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Drain-Sou	Drain-Source Diode Characteristics						
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V, } I_S = 3 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V, } I_S = -2.3 \text{ A}$ (Note 2)			0.86 -0.82	1.3 -1.3	V
t _{rr}	Reverse Recovery Time	Q1/Q4: I _F = 3 A, di/dt = 100 A/μs	Q1/Q4 Q2/Q3		32 26	52 42	ns
Q _{rr}	Reverse Recovery Charge	Q2/Q3: I _F = -2.3 A, di/dt = 100 A/μs	Q1/Q4 Q2/Q3		21 26	34 42	nC

Notes:

13. R_{0,JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,JC} is guaranteed by design while R_{0,CA} is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in 2 pad of 2 oz copper, the board designed Q1+Q3 or Q2+Q4.



b. 160 °C/W when mounted on a minimum pad of 2 oz copper, the board designed Q1+Q3 or Q2+Q4.

2: Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.

Typical Characteristics (N-Channel) T, = 25 °C unless otherwise noted

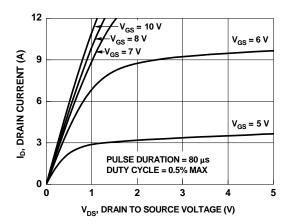


Figure 1. On Region Characteristics

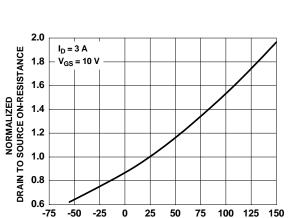


Figure 3. Normalized On Resistance vs Junction Temperature

TJ, JUNCTION TEMPERATURE (°C)

0 25 50 75 100

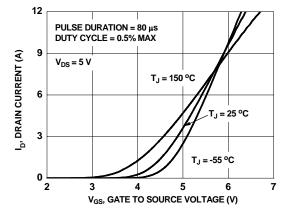


Figure 5. Transfer Characteristics

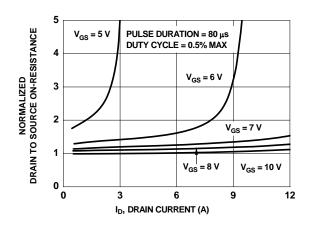


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

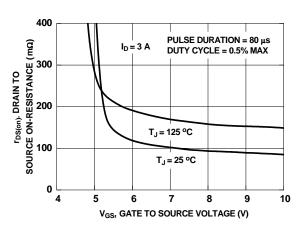


Figure 4. On-Resistance vs Gate to Source Voltage

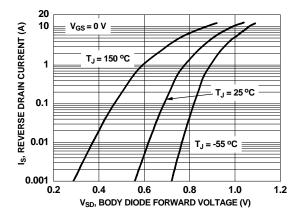


Figure 6. Source to Drain Diode **Forward Voltage vs Source Current**

-75

Typical Characteristics (N-Channel) $T_J = 25 \text{ } \text{C}$ unless otherwise noted

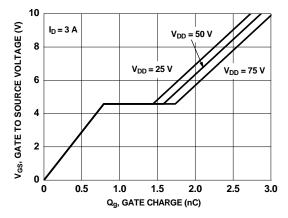


Figure 7. Gate Charge Characteristics

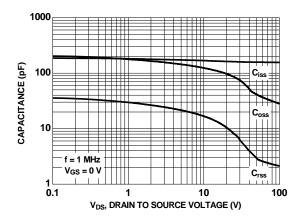


Figure 8. Capacitance vs Drain to Source Voltage

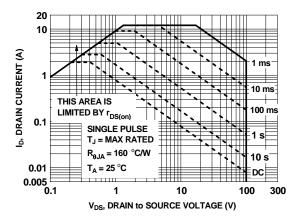
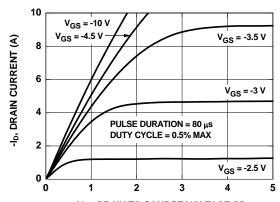


Figure 9. Forward Bias Safe Operating Area

Typical Characteristics (P-Channel) $T_J = 25$ °C unlenss otherwise noted



-V_{DS}, DRAIN TO SOURCE VOLTAGE (V) Figure 10. On-Region Characteristics

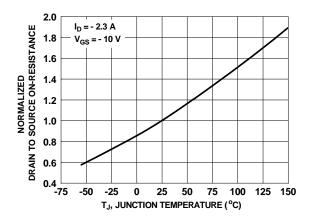


Figure 12. Normalized On-Resistance vs Junction Temperature

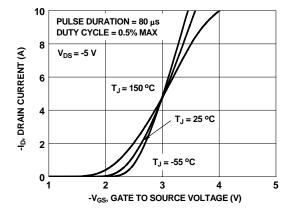


Figure 14. Transfer Characteristics

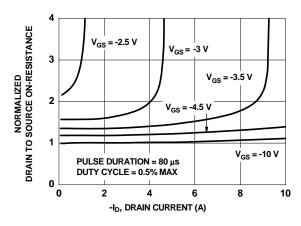


Figure 11. Normalized on-Resistance vs Drain Current and Gate Voltage

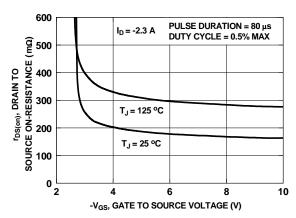


Figure 13. On-Resistance vs Gate to Source Voltage

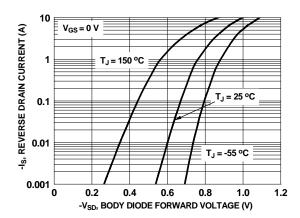


Figure 15. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (P-Channel) $T_J = 25$ °C unlenss otherwise noted

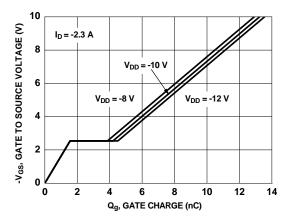


Figure 16. Gate Charge Characteristics

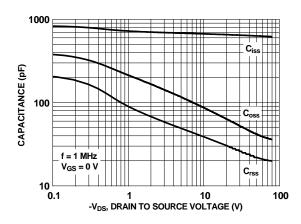


Figure 17. Capacitance vs Drain to Source Voltage

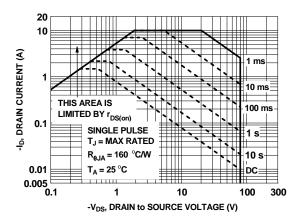


Figure 18. Forward Bias Safe Operating Area

Typical Characteristics $T_J = 25$ °C unlenss otherwise noted

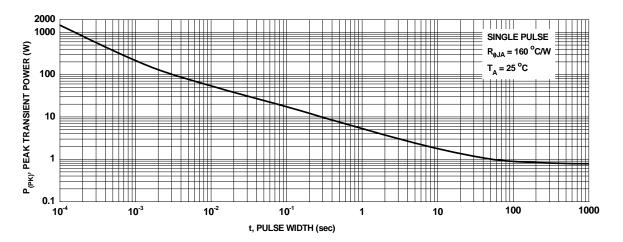


Figure 19. Single Pulse Maximum Power Dissipation

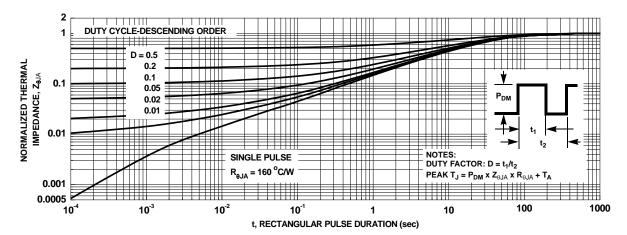
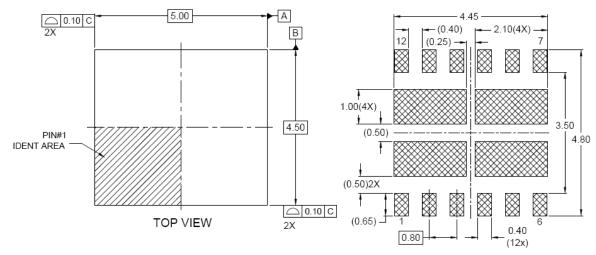
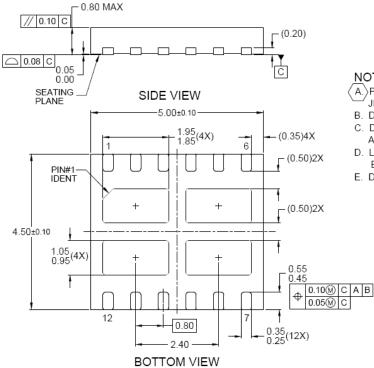


Figure 20. Junction-to-Ambient Transient Thermal Response Curve

Dimensional Outline and Pad Layout







NOTES:

- A. PACKAGE DOES NOT FULLY CONFORM TO JEDEC MO-229 REGISTRATION
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
- LAND PATTERN RECOMMENDATION IS BASED ON FSC DESIGN ONLY.
- E. DRAWING FILENAME: MKT-MLP12Erev2.





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